IGBT

High speed 5 FAST IGBT in TRENCHSTOP^{TM} 5 technology copacked with RAPID 1 fast and soft anti parallel diode

IKP40N65F5, IKW40N65F5

650V DuoPack IGBT and Diode
High speed switching series fifth generation

Data sheet

Industrial Power Control
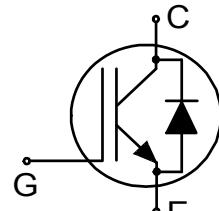
High speed 5 FAST IGBT in TRENCHSTOP™ 5 technology copacked with RAPID 1 fast and soft anti parallel diode

**Features and Benefits:**

High speed F5 technology offering
• Best-in-Class efficiency in hard switching and resonant topologies
• 650V breakdown voltage
• Low Q_g
• IGBT copacked with RAPID 1 fast and soft antiparallel diode
• Maximum junction temperature 175°C
• Qualified according to JEDEC for target applications
• Pb-free lead plating; RoHS compliant
• Complete product spectrum and PSpice Models:
http://www.infineon.com/igbt/

Applications:

• Solar converters
• Uninterruptible power supplies
• Welding converters
• Mid to high range switching frequency converters

Package pin definition:

• Pin 1 - gate
• Pin 2 & backside - collector
• Pin 3 - emitter

Key Performance and Package Parameters

Type	V_{CE}	I_C	V_{CEsat}, T_{vj}=25°C	T_{vjmax}	Marking	Package
IKW40N65F5	650V	40A	1.6V	175°C	K40EF5	PG-TO247-3
IKP40N65F5	650V	40A	1.6V	175°C	K40EF5	PG-TO220-3

Table of Contents

IKW40N65F5, IKP40N65F5

High speed switching series fifth generation

Maximum ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	650	V
DC collector current, limited by T_{vjmax} T_C = 25°C T_C = 100°C	I_C	74.0 46.0	A
Pulsed collector current, t_p limited by T_{vjmax}	I_{Cpuls}	120.0	A
Turn off safe operating area $V_{CE} \leq 650V$, $T_{vj} \leq 175$°C	-	120.0	A
Diode forward current, limited by T_{vjmax} T_C = 25°C T_C = 100°C	I_F	36.0 21.0	A
Diode pulsed current, t_p limited by T_{vjmax}	I_{Fpuls}	120.0	A
Gate-emitter voltage Transient Gate-emitter voltage ($t_p \leq 10$µs, D < 0.010)	V_{GE}	±20 ±30	V
Power dissipation T_C = 25°C Power dissipation T_C = 100°C	P_{tot}	255.0 120.0	W
Operating junction temperature	T_{vj}	-40...+175	°C
Storage temperature	T_{stg}	-55...+150	°C
Soldering temperature, wave soldering 1.6 mm (0.063 in.) from case for 10s	PG-TO247-pinGCE PG-TO220-3	260 260	°C
Mounting torque, M3 screw Maximum of mounting processes: 3	M	0.6	Nm

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
IGBT thermal resistance, junction - case	$R_{th(j-c)}$		0.60	K/W
Diode thermal resistance, junction - case	$R_{th(j-c)}$		1.80	K/W
Thermal resistance junction - ambient	$R_{th(j-a)}$	PG-TO247-pinGCE PG-TO220-3	40 62	K/W

Electrical Characteristic, at T_{vj} = 25°C, unless otherwise specified

Parameter	Symbol	Conditions	Value min.	Value typ.	Value max.	Unit
Static Characteristic						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	V_{GE} = 0V, I_C = 0.20mA	650	-	-	V
Collector-emitter saturation voltage	V_{CEsat}	V_{GE} = 15.0V, I_C = 40.0A T_{vj} = 25°C T_{vj} = 125°C T_{vj} = 175°C	- - -	1.60 1.80 1.90	2.10 - -	V
Diode forward voltage	V_F	V_{GE} = 0V, I_F = 20.0A T_{vj} = 25°C T_{vj} = 125°C T_{vj} = 175°C	- - -	1.45 1.40 1.40	1.80 - -	V
Gate-emitter threshold voltage	$V_{GE(th)}$	I_C = 0.40mA, V_{CE} = V_{GE}	3.2	4.0	4.8	V
Zero gate voltage collector current	I_{CES}	V_{CE} = 650V, V_{GE} = 0V T_{vj} = 25°C T_{vj} = 175°C	- -	- -	40.0 4000.0	μA
Gate-emitter leakage current	I_{GES}	V_{CE} = 0V, V_{GE} = 20V	-	-	100	nA
Transconductance	g_{fs}	V_{CE} = 20V, I_C = 40.0A	-	50.0	-	S

Electrical Characteristic, at T_{vj} = 25°C, unless otherwise specified

Parameter	Symbol	Conditions	Value min.	Value typ.	Value max.	Unit
Dynamic Characteristic						
Input capacitance	C_{ies}	V_{CE} = 25V, V_{GE} = 0V, f = 1MHz	-	2500	-	pF
Output capacitance	C_{oes}		-	50	-	pF
Reverse transfer capacitance	C_{res}		-	9	-	pF
Gate charge	Q_G	V_{CC} = 520V, I_C = 40.0A, V_{GE} = 15V	-	95.0	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	L_E	PG-TO247-pinGCE PG-TO220-3	-	13.0	-	nH

Switching Characteristic, Inductive Load

Parameter	Symbol	Conditions	Value min.	Value typ.	Value max.	Unit
IGBT Characteristic, at T_{vj} = 25°C						
Turn-on delay time	$t_{d(on)}$	T_{vj} = 25°C, V_{CC} = 400V, I_C = 20.0A, V_{GE} = 0.0/15.0V, r_G = 15.0Ω, $L\sigma$ = 30nH, $C\sigma$ = 30pF $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	19	-	ns
Rise time	t_r		-	13	-	ns
Turn-off delay time	$t_{d(off)}$		-	160	-	ns
Fall time	t_f		-	16	-	ns
Turn-on energy	E_{on}		-	0.36	-	mJ
Turn-off energy	E_{off}		-	0.10	-	mJ
Total switching energy	E_{ts}		-	0.46	-	mJ

Turn-on delay time	$t_{d(on)}$	T_{vj} = 25°C, V_{CC} = 400V, I_C = 5.0A, V_{GE} = 0.0/15.0V, r_G = 15.0Ω, $L\sigma$ = 30nH, $C\sigma$ = 30pF $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	20	-	ns
Rise time	t_r		-	4	-	ns
Turn-off delay time	$t_{d(off)}$		-	175	-	ns
Fall time	t_f		-	10	-	ns
Turn-on energy	E_{on}		-	0.07	-	mJ
Turn-off energy	E_{off}		-	0.03	-	mJ
Total switching energy	E_{ts}		-	0.10	-	mJ

Diode Characteristic, at T_{vj} = 25°C

Diode reverse recovery time	t_{rr}	T_{vj} = 25°C, V_R = 400V, I_F = 20.0A, di_F/dt = 1000A/µs	-	60	-	ns
Diode reverse recovery charge	Q_{rr}		-	0.45	-	µC
Diode peak reverse recovery current	I_{rrm}		-	12.4	-	A
Diode peak rate of fall of reverse recovery current during t_b	di_{rr}/dt		-	-280	-	A/µs

Diode reverse recovery time	t_{rr}	T_{vj} = 25°C, V_R = 400V, I_F = 5.0A, di_F/dt = 1000A/µs	-	33	-	ns
Diode reverse recovery charge	Q_{rr}		-	0.22	-	µC
Diode peak reverse recovery current	I_{rrm}		-	10.6	-	A
Diode peak rate of fall of reverse recovery current during t_b	di_{rr}/dt		-	-1030	-	A/µs

Switching Characteristic, Inductive Load
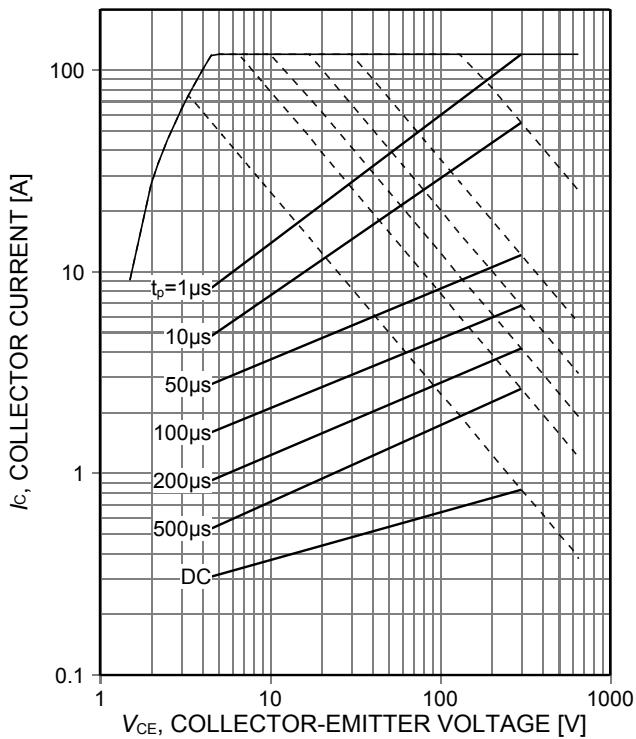
Parameter	Symbol	Conditions	Value min.	Value typ.	Value max.	Unit

IGBT Characteristic, at T_{vj} = 150°C
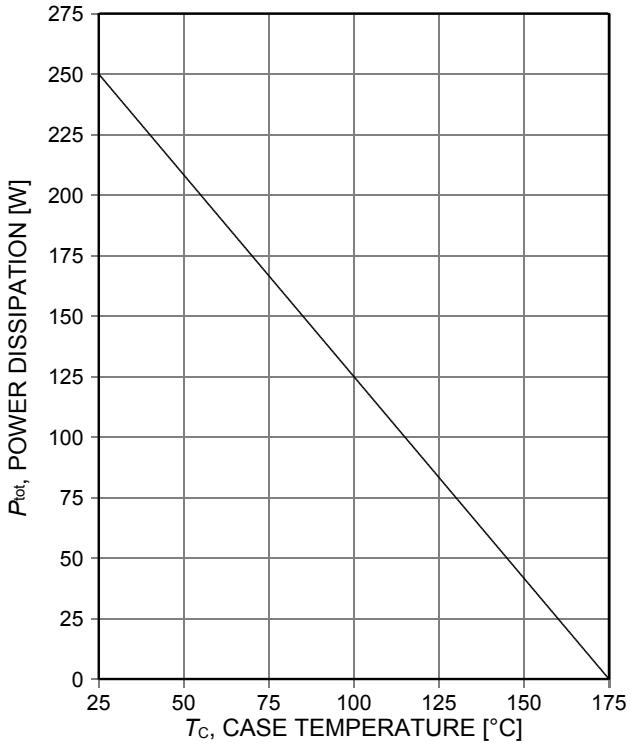
Turn-on delay time	$t_{d(on)}$	T_{vj} = 150°C, V_{CC} = 400V, I_C = 20.0A, V_{GE} = 0.0/15.0V, r_G = 15.0Ω, $L\sigma$ = 30nH, $C\sigma$ = 30pF $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	20	-	ns
Rise time	t_r		-	14	-	ns
Turn-off delay time	$t_{d(off)}$		-	185	-	ns
Fall time	t_f		-	15	-	ns
Turn-on energy	E_{on}		-	0.50	-	mJ
Turn-off energy	E_{off}		-	0.16	-	mJ
Total switching energy	E_{ts}		-	0.66	-	mJ

Turn-on delay time	$t_{d(on)}$	T_{vj} = 150°C, V_{CC} = 400V, I_C = 5.0A, V_{GE} = 0.0/15.0V, r_G = 15.0Ω, $L\sigma$ = 30nH, $C\sigma$ = 30pF $L\sigma$, $C\sigma$ from Fig. E Energy losses include "tail" and diode reverse recovery.	-	18	-	ns
Rise time	t_r		-	5	-	ns
Turn-off delay time	$t_{d(off)}$		-	220	-	ns
Fall time	t_f		-	12	-	ns
Turn-on energy	E_{on}		-	0.14	-	mJ
Turn-off energy	E_{off}		-	0.05	-	mJ
Total switching energy	E_{ts}		-	0.19	-	mJ

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Diode Characteristic, at T_{vj} = 150°C
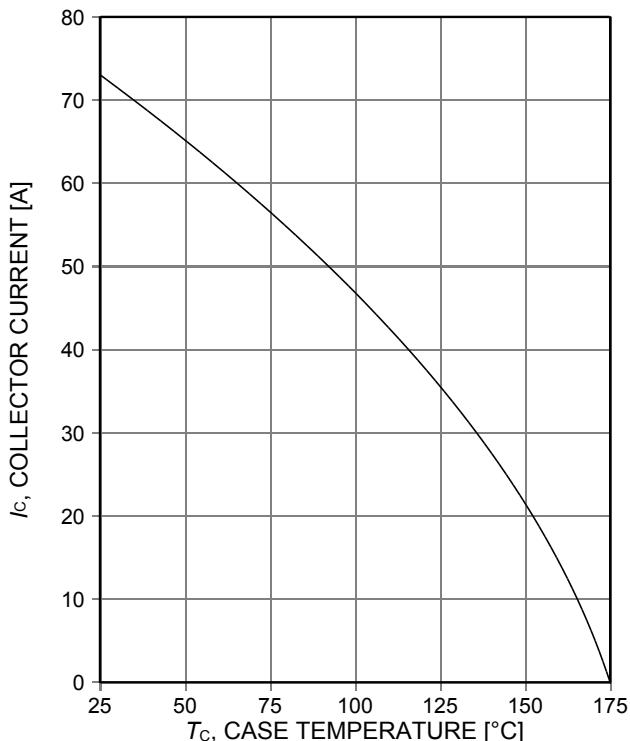
Diode reverse recovery time	t_{rr}	T_{vj} = 150°C, V_R = 400V, I_F = 20.0A, di_F/dt = 1000A/µs	-	85	-	ns
Diode reverse recovery charge	Q_{rr}		-	1.00	-	µC
Diode peak reverse recovery current	I_{rrm}		-	17.0	-	A
Diode peak rate of fall of reverse recovery current during t_b	di_{rr}/dt		-	-220	-	A/µs
Diode reverse recovery time	t_{rr}	T_{vj} = 150°C, V_R = 400V, I_F = 5.0A, di_F/dt = 1000A/µs	-	50	-	ns
Diode reverse recovery charge	Q_{rr}		-	0.50	-	µC
Diode peak reverse recovery current	I_{rrm}		-	14.0	-	A
Diode peak rate of fall of reverse recovery current during t_b	di_{rr}/dt		-	-500	-	A/µs

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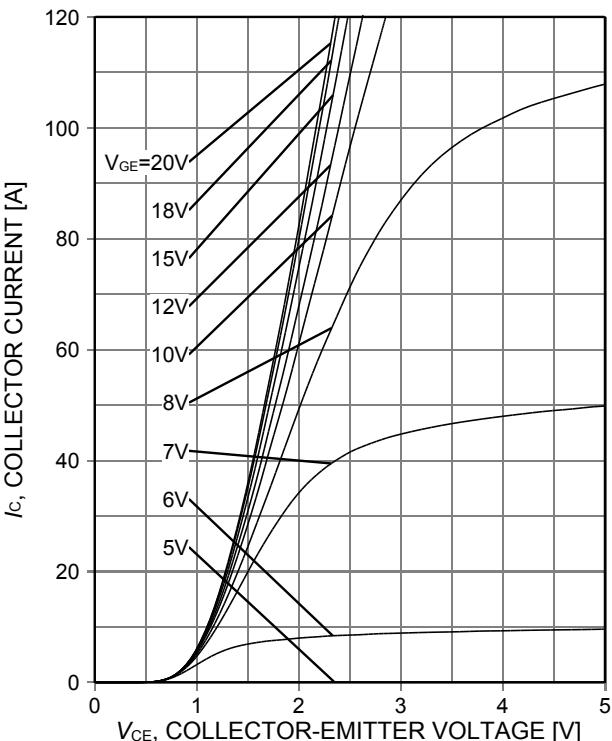
Figure 1. **Forward bias safe operating area**
(D=0, T_C=25°C, T_{vj}≤175°C; V_{GE}=15V.
Recommended use at V_{GE}≥7.5V)
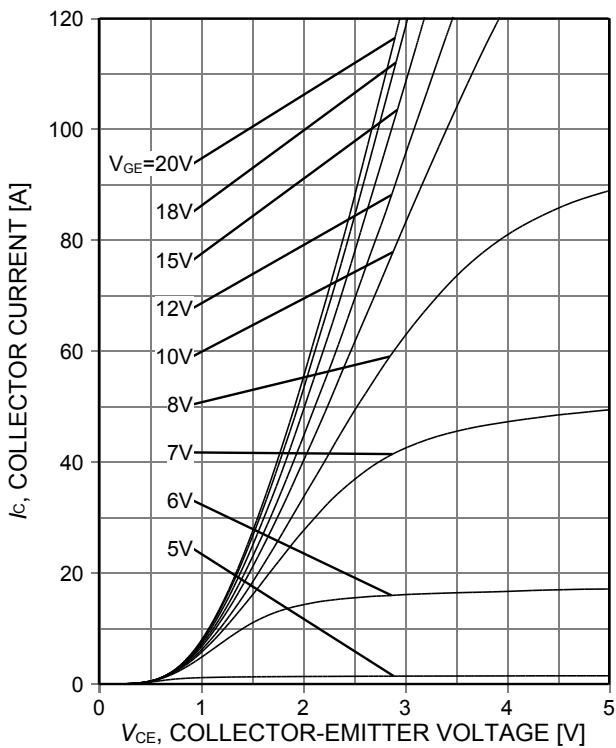
Figure 2. **Power dissipation as a function of case temperature**
(T_{vj}≤175°C)
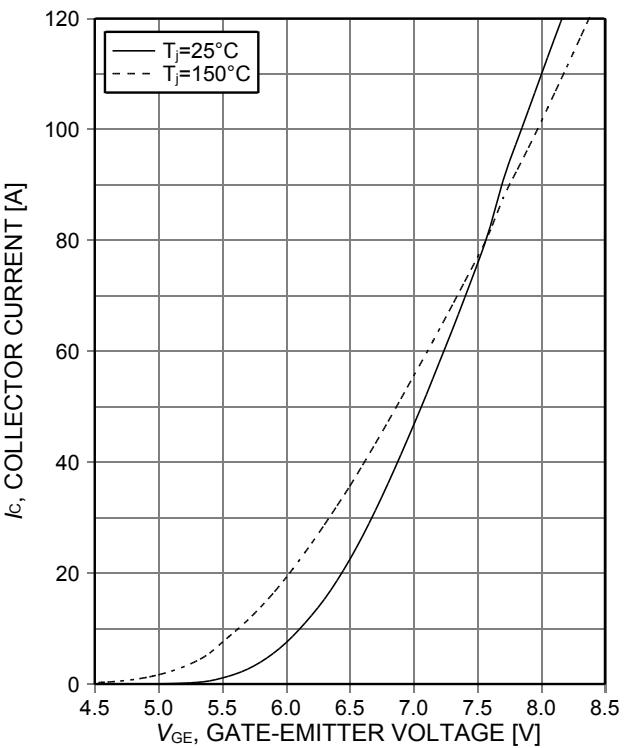
Figure 3. **Collector current as a function of case temperature**
(V_{GE}≥15V, T_{vj}≤175°C)
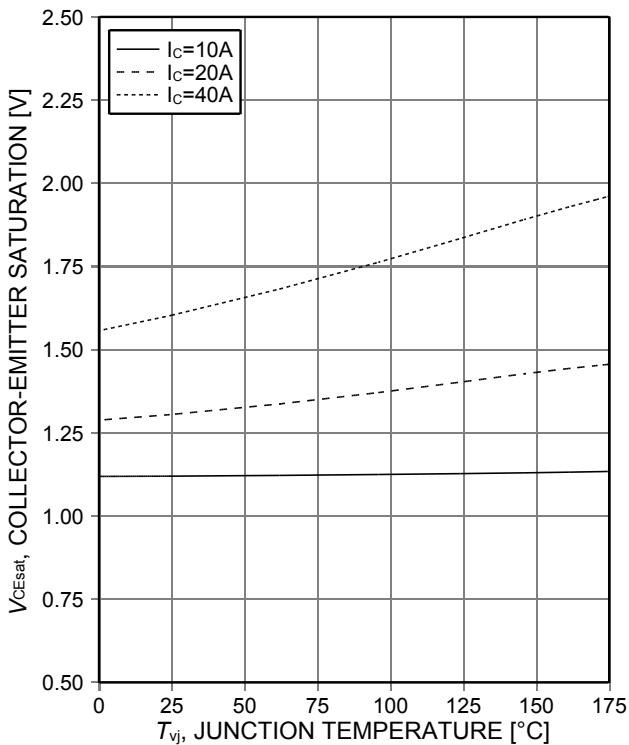
Figure 4. **Typical output characteristic**
(T_{vj}=25°C)

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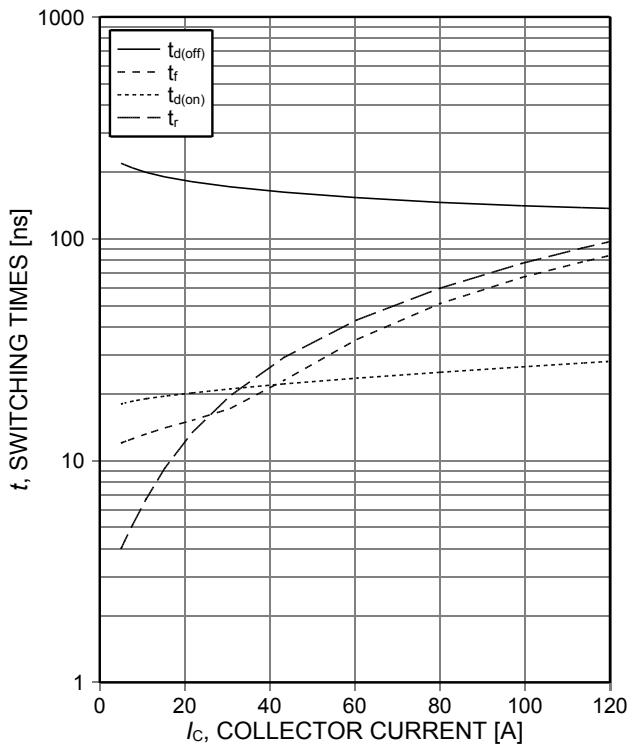
Figure 5. **Typical output characteristic**
(T_{vj}=150°C)

Figure 6. **Typical transfer characteristic**
(V_{CE}=20V)

Figure 7. **Typical collector-emitter saturation voltage as a function of junction temperature**
(V_{GE}=15V)

Figure 8. **Typical switching times as a function of collector current**
(inductive load, T_{vj}=150°C, V_{CE}=400V, V_{GE}=15/0V, r_G=15Ω, Dynamic test circuit in Figure E)

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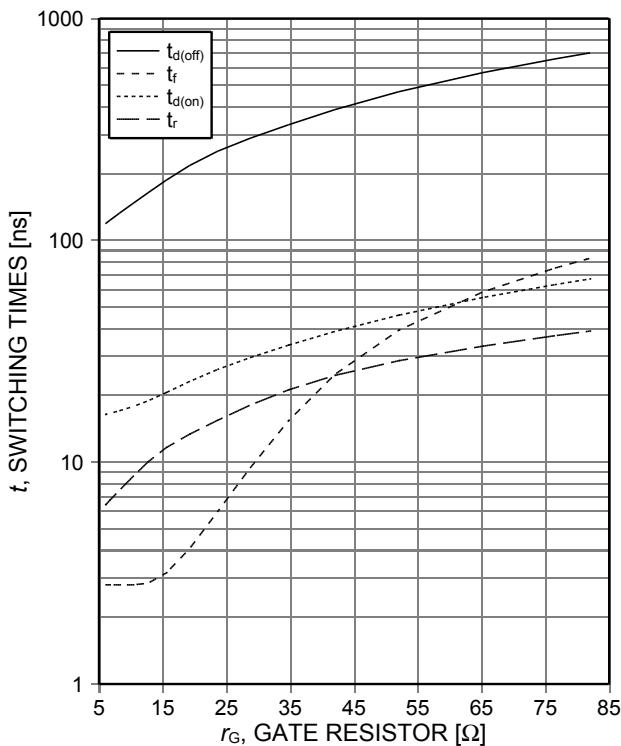
Figure 9. **Typical switching times as a function of gate resistor**
(inductive load, T_{vj}=150°C, V_{CE}=400V, V_{GE}=15/0V, I_C=20A,Dynamic test circuit in Figure E)
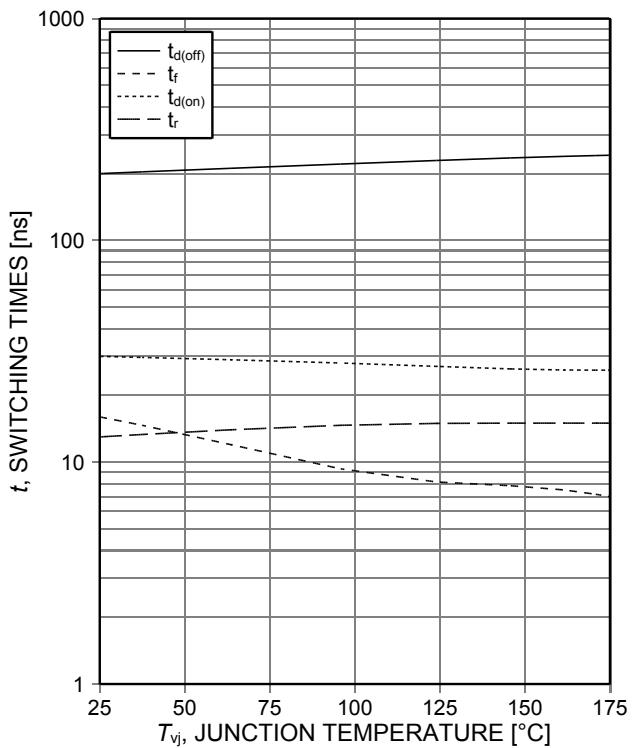
Figure 10. **Typical switching times as a function of junction temperature**
(inductive load, V_{CE}=400V, V_{GE}=15/0V, I_C=20A, r_G=15Ω,Dynamic test circuit in Figure E)
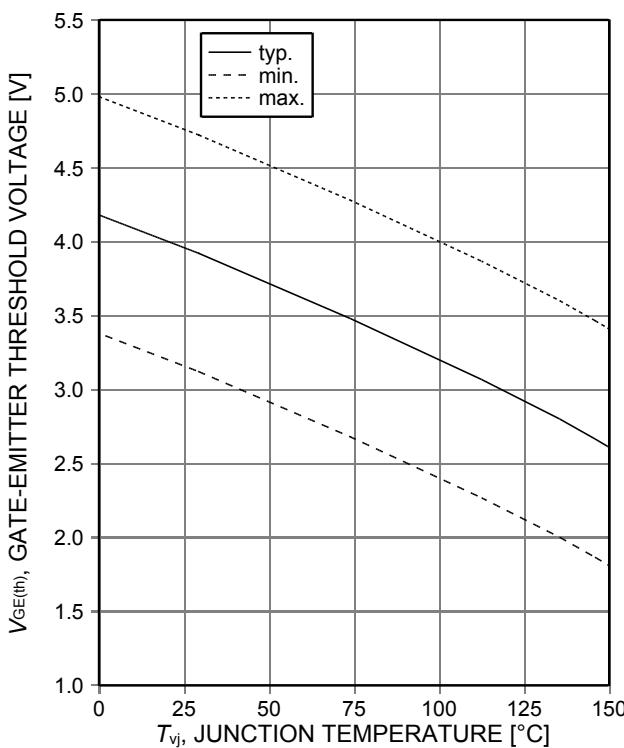
Figure 11. **Gate-emitter threshold voltage as a function of junction temperature**
(I_C=0.4mA)
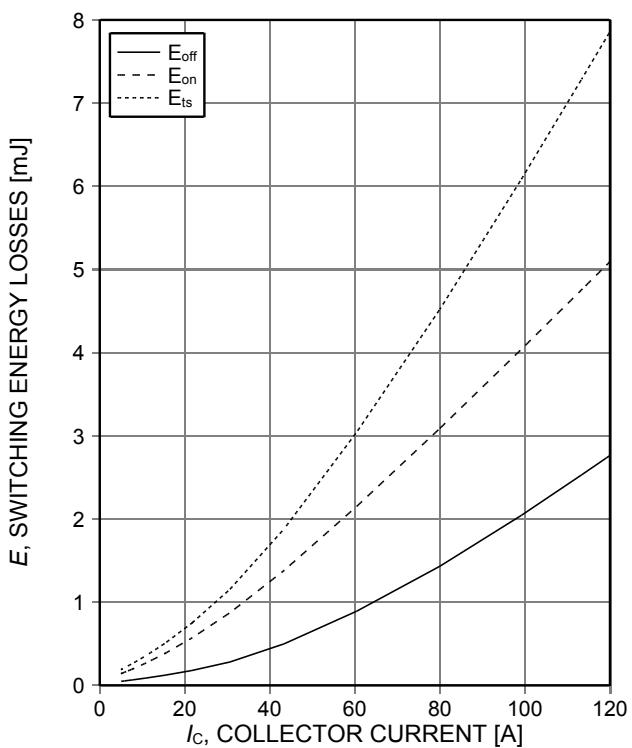
Figure 12. **Typical switching energy losses as a function of collector current**
(inductive load, T_{vj}=150°C, V_{CE}=400V, V_{GE}=15/0V, r_G=15Ω,Dynamic test circuit in Figure E)

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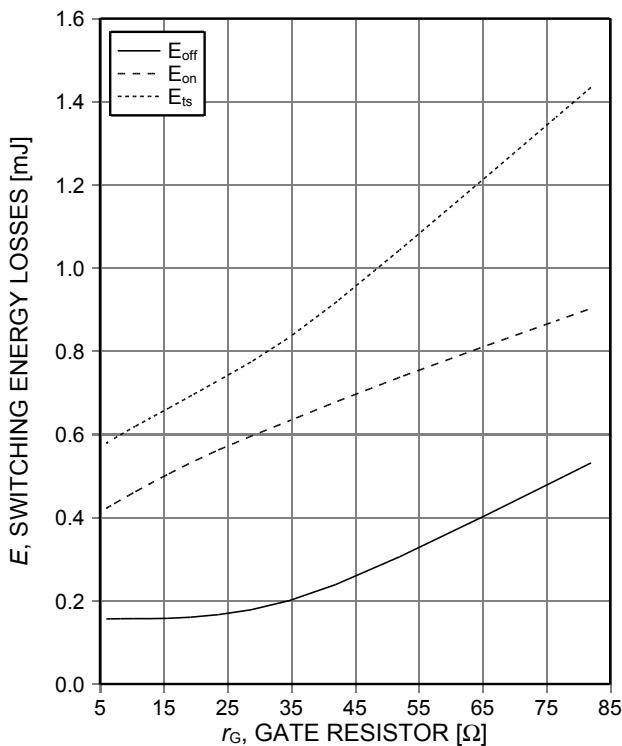
Figure 13. **Typical switching energy losses as a function of gate resistor** (inductive load, T_{vj}=150°C, V_{CE}=400V, V_{GE}=15/0V, I_C=20A, Dynamic test circuit in Figure E)
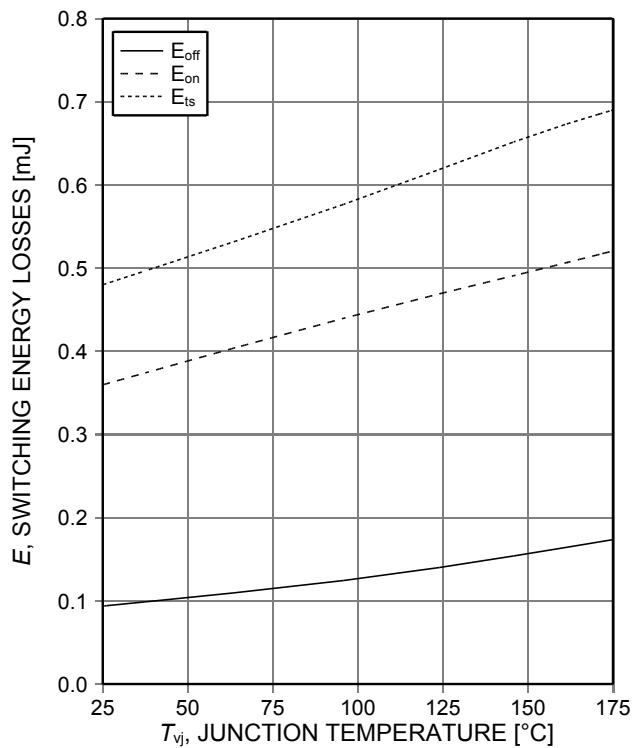

Figure 14. **Typical switching energy losses as a function of junction temperature** (inductive load, V_{CE}=400V, V_{GE}=15/0V, I_C=20A, r_G=15Ω, Dynamic test circuit in Figure E)
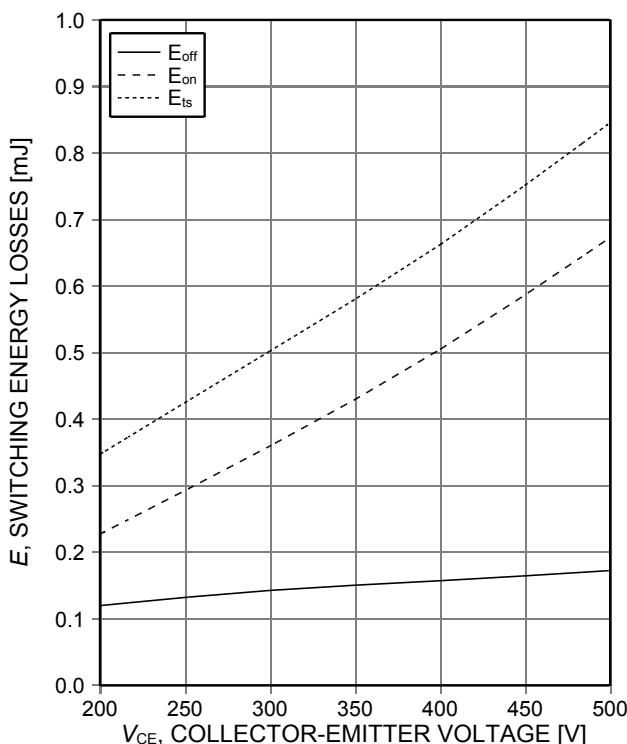
Figure 15. **Typical switching energy losses as a function of collector emitter voltage** (inductive load, T_{vj}=150°C, V_{GE}=15/0V, I_C=20A, r_G=15Ω, Dynamic test circuit in Figure E)
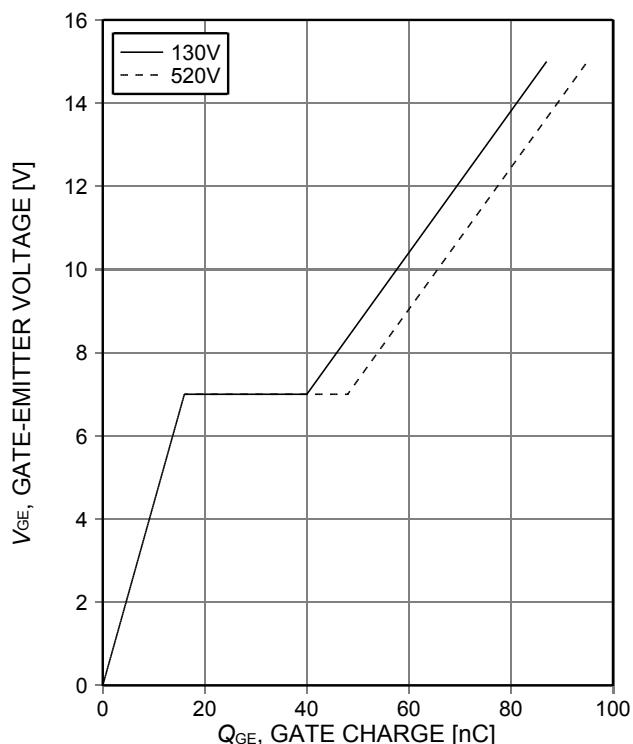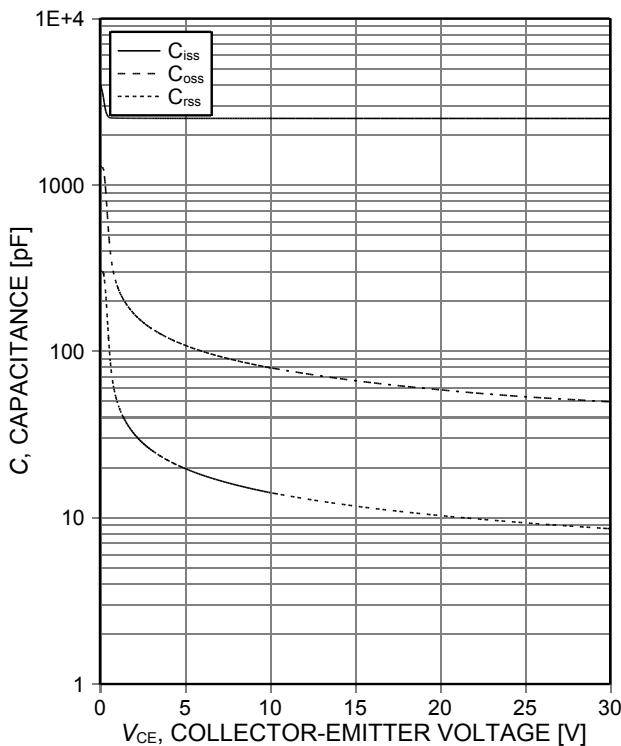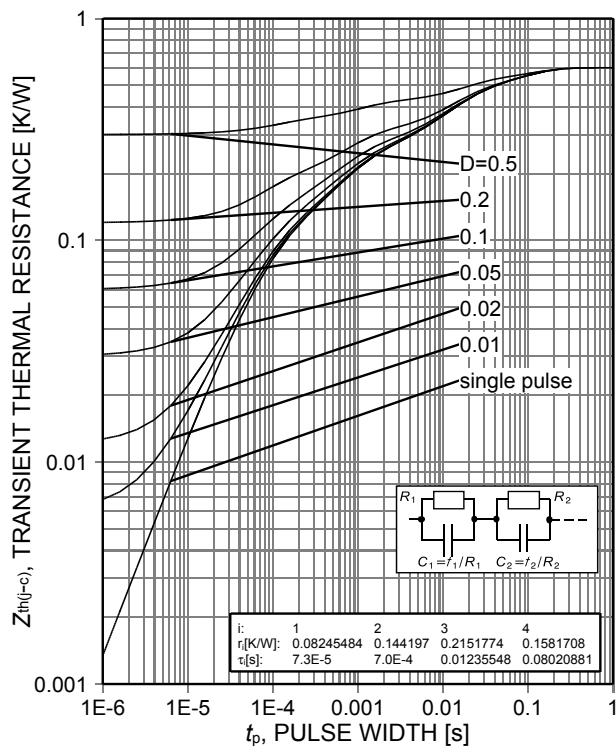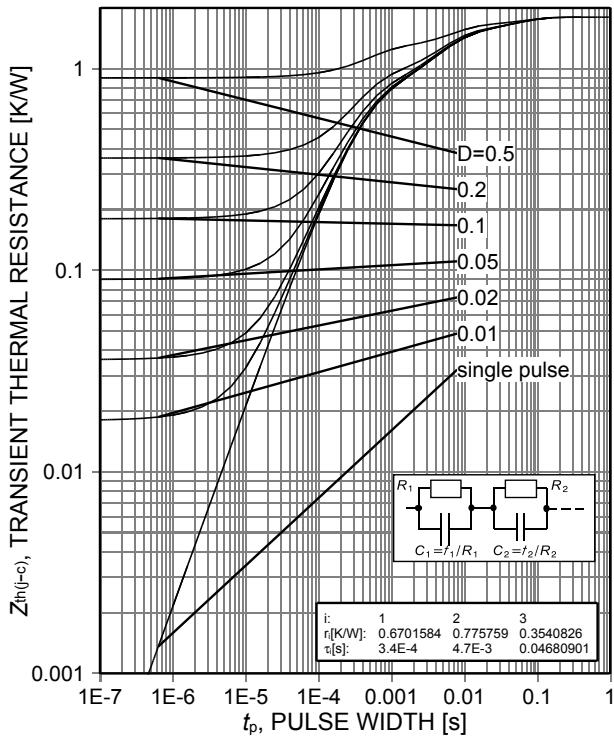
Figure 16. **Typical gate charge** (I_C=40A)

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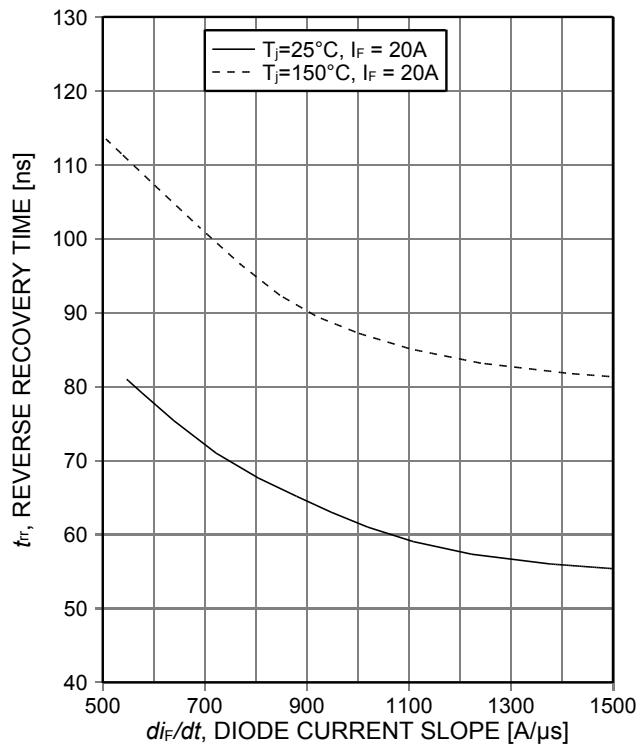
Figure 17. **Typical capacitance as a function of collector-emitter voltage**
(V_{GE}=0V, f=1MHz)

Figure 18. **IGBT transient thermal resistance**
($D=t_p/T$)

Figure 19. **Diode transient thermal impedance as a function of pulse width**
($D=t_p/T$)

Figure 20. **Typical reverse recovery time as a function of diode current slope**
(V_R=400V)

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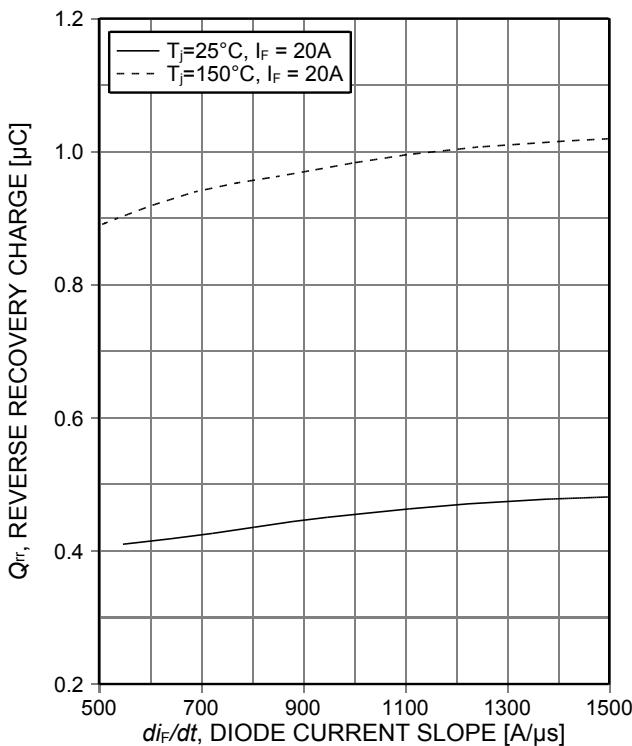
Figure 21. **Typical reverse recovery charge as a function of diode current slope** (V_R=400V)
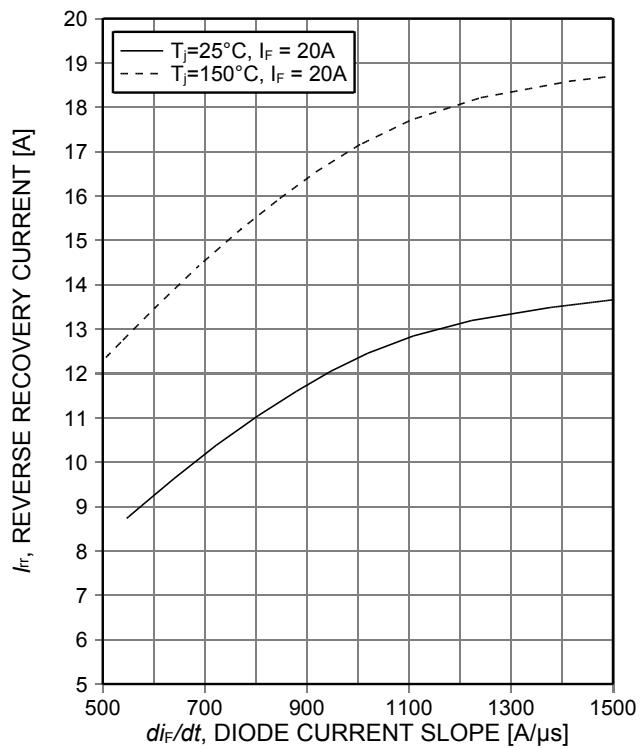

Figure 22. **Typical reverse recovery current as a function of diode current slope** (V_R=400V)
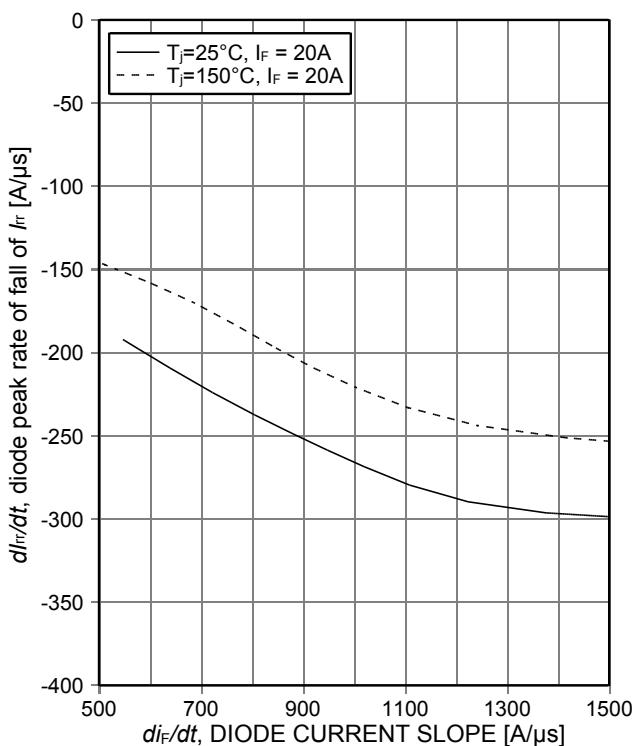

Figure 23. **Typical diode peak rate of fall of reverse recovery current as a function of diode current slope** (V_R=400V)
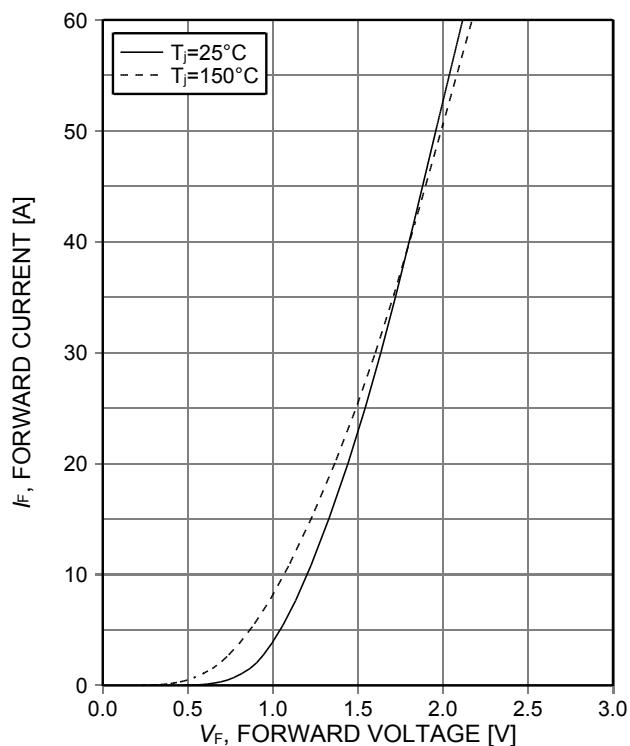

Figure 24. **Typical diode forward current as a function of forward voltage**
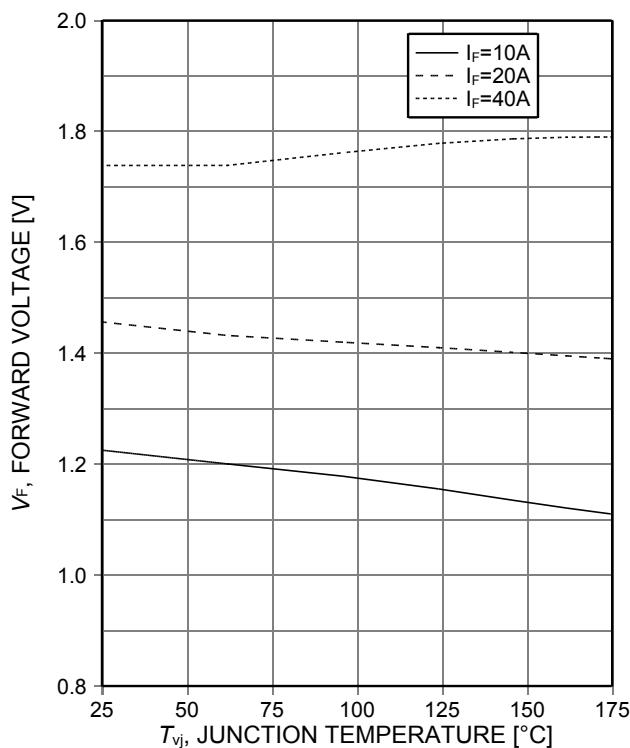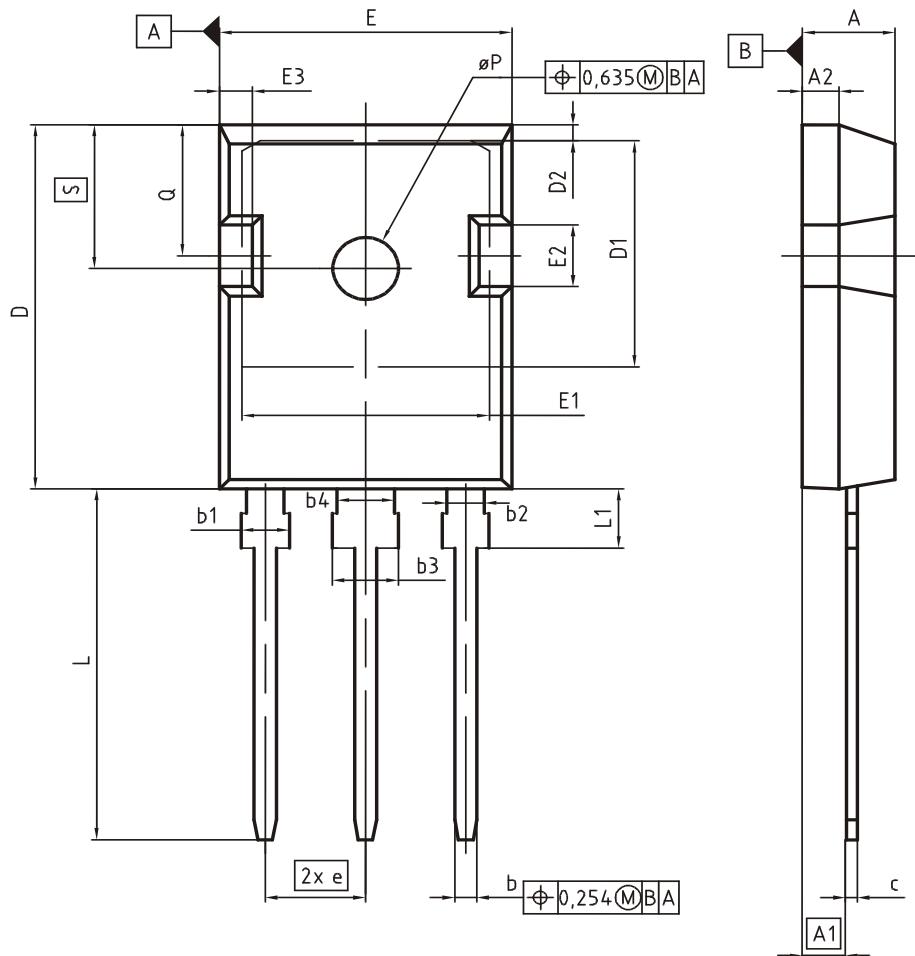
Figure 25. **Typical diode forward voltage as a function of junction temperature**
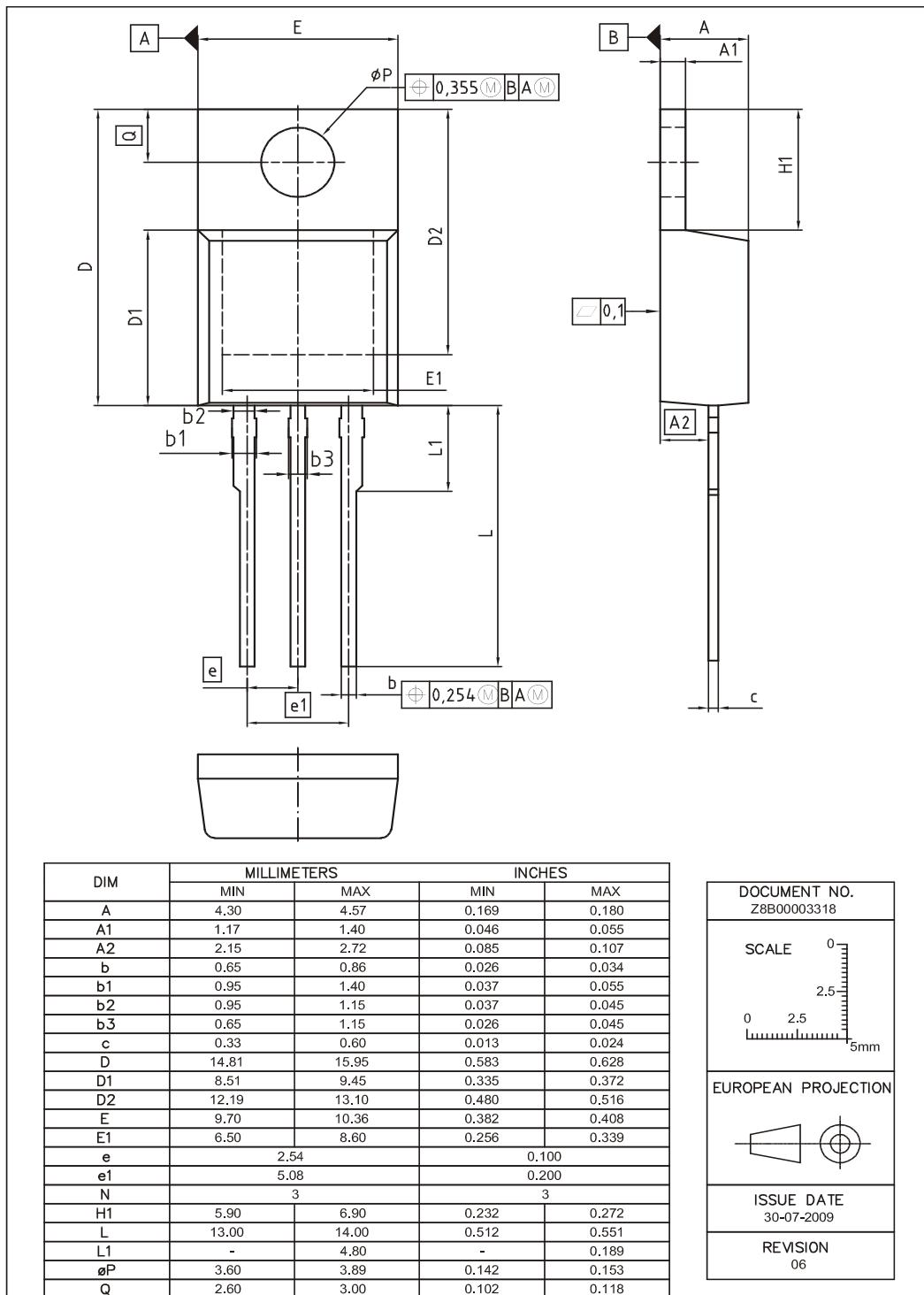
PG-TO247-3

| DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.83	5.21	0.190	0.205
A1	2.27	2.54	0.089	0.100
A2	1.85	2.16	0.073	0.085
b	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
c	0.55	0.68	0.022	0.027
D	20.80	21.10	0.819	0.831
D1	16.25	17.65	0.640	0.695
D2	0.95	1.35	0.037	0.053
E	15.70	16.13	0.618	0.635
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.00	2.60	0.039	0.102
e	5.44 (BSC)		0.214 (BSC)	
N	3		3	
L	19.80	20.32	0.780	0.800
L1	4.10	4.47	0.161	0.176
øP	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238	0.248

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SCALE

**EUROPEAN PROJECTION**

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REVISION
05

PG-TO220-3

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
b1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
c	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øP	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

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06

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Figure A. Definition of switching times
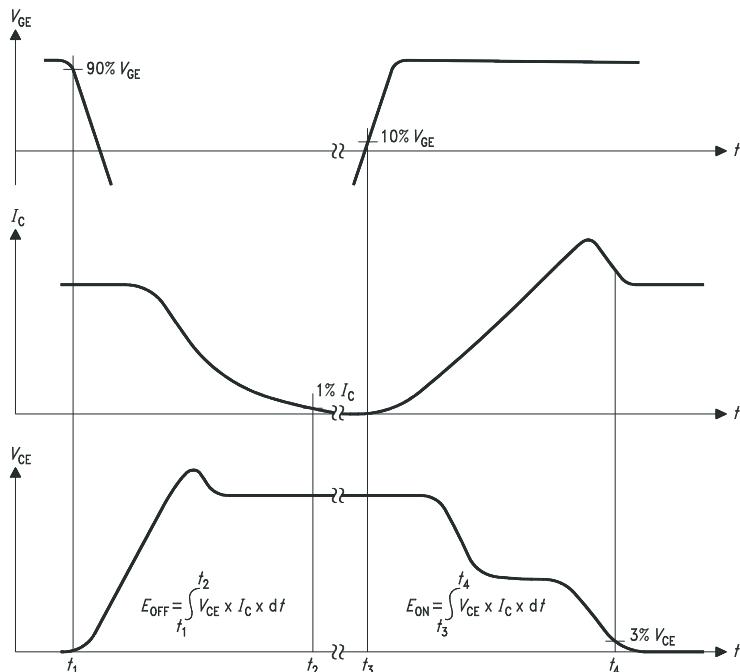
Figure B. Definition of switching losses

$$E_{OFF} = \int_{t_1}^{t_2} V_{CE} \times I_C \times dt$$

$$E_{ON} = \int_{t_3}^{t_4} V_{CE} \times I_C \times dt$$
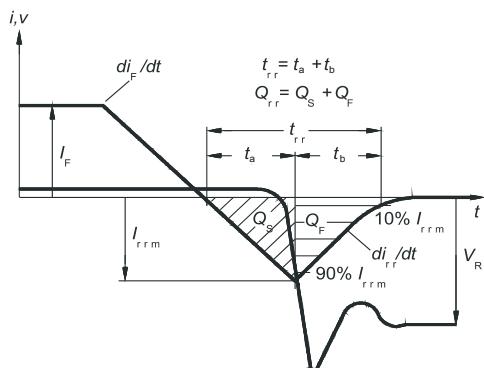
Figure C. Definition of diodes switching characteristics

$$t_{rr} = t_a + t_b$$
$$Q_{rr} = Q_S + Q_F$$
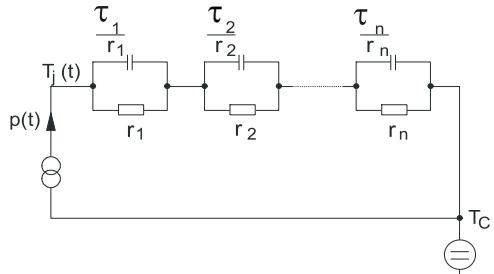
Figure D. Thermal equivalent circuit
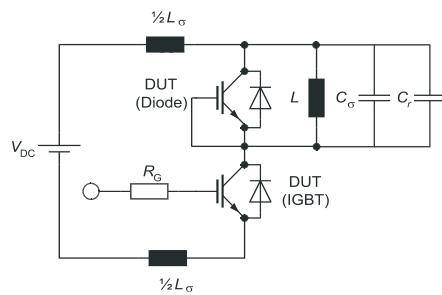
Figure E. Dynamic test circuit
Parasitic inductance L_σ ,
Parasitic capacitor C_σ ,
Relief capacitor C_r
(only for ZVT switching)

Revision History

IKW40N65F5, IKP40N65F5

Revision: 2013-12-18, Rev. 1.2

Previous Revision

Revision	Date	Subjects (major changes since last revision)
1.1	2012-11-09	Preliminary data sheet
1.2	2013-12-18	New Marking Pattern

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